Abstracts

Noise Characterization Uncertainty of Microwave Devices Under Low Current Operation

R. Lucero, C. Moyer, R. Vaitkus and M. Dydyk. "Noise Characterization Uncertainty of Microwave Devices Under Low Current Operation." 1989 MTT-S International Microwave Symposium Digest 89.3 (1989 Vol. III [MWSYM]): 893-895.

An automated source reflection coefficient synthesizer combined with mechanical output tuner was used in conjunction with gage capability studies for the noise parameters of GaAs MESFETs and planar-doped psuedomorphic MODFETs operating at low currents (Ids <1 mA). The net repeatability and reproducibility (99% confidence interval for the test) of the measurement system was established at ±0.2 dB and ±1.4 dB for the minimum noise figure and associated gain, respectively.

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